

REMARKS

The Examiner is thanked for the thorough examination of the present application. The Office Action, however, continued to reject all examined claims. In response, Applicant submits the foregoing amendments and the following remarks. Specifically, claims 1, 16, and 31 have been amended to more clearly define over the cited art. Claims 2 and 53 are cancelled. Applicant submits that no new matter is added by these amendments. Applicant submits that the amendments to independent claims 1, 16, and 31 have rendered these claims moot. Notwithstanding, Applicant submits the following distinguishing remarks.

Rejections under 35 U.S.C 103(a)

Claims 1-4, 8, 11, 12, 15-19, 23, 26, 27, 29-34, 38, 41, 42, 44, 45 and 53 are rejected under 35 U.S.C 103(a) as allegedly being unpatentable over US patent 7,237,266 to Aaron. Applicant respectfully requests reconsideration and withdrawal of these rejections.

With regard to the independent claims 1, 16, and 31, these claims have been amended herein to respectively recite:

1. A reliability assessment system for assessing a reliability of a semiconductor product, comprising:
a web-based interface ***providing selections corresponding to assessment items***, to receive a specific selection from the selections for the semiconductor product ***via a network, receive a selection of at least one specific data item among data items for the assessment item corresponding to the specific selection via the network, and receive input items corresponding to the data items without the specific data item via the network***, wherein the respective assessment item comprises a manufacturing process for the semiconductor product; and

an assessment engine to perform a reliability assessment for the semiconductor product toward the assessment item corresponding to the selected specific selection according to the input items and the manufacturing process of the assessment item corresponding to the selected specific selection, generate a result of the reliability assessment, and display the result on the interface, ***wherein the result comprises at least one output item for the specific data item*** of the assessment item corresponding to the selected specific selection.

16. A computerized reliability assessment method for assessing a reliability of a semiconductor product, comprising the steps of:

providing selections corresponding to assessment items by a web-based interface, wherein the respective assessment item comprises a manufacturing process for the semiconductor product;

receiving a specific selection from the selections for the semiconductor product ***via a network***;

receiving a selection of at least one specific data item among data items for the assessment item corresponding to the specific selection via the network;

receiving input items corresponding to the data items without the specific data item via the network;

performing a reliability assessment for the semiconductor product toward the assessment item corresponding to the selected specific selection according to the input items and the manufacturing process of the assessment item corresponding to the selected specific selection; and

generating a result of the reliability assessment, ***wherein the result comprises at least one output item for the specific data item*** of the assessment item corresponding to the selected specific selection.

31. A machine-readable storage medium storing a computer program which, when executed, directs a computer to perform a method of reliability assessment for assessing a reliability of a semiconductor product, comprising the steps of:

providing selections corresponding to assessment items by a web-based interface, wherein the respective assessment item comprises a manufacturing process for the semiconductor product;

receiving a specific selection from the selections for the semiconductor product ***via a network***;

receiving a selection of at least one specific data item among data items for the assessment item corresponding to the specific selection via the network;
receiving input items corresponding to the data items without the specific data item via the network;
performing a reliability assessment for the semiconductor product toward the assessment item corresponding to the selected specific selection according to the input items and the manufacturing process of the assessment item corresponding to the selected specific selection; and generating a result of the reliability assessment, **wherein the result comprises at least one output item for the specific data item** of the assessment item corresponding to the selected specific selection.

(*Emphasis added*). Independent claims 1, 16, and 31 patently defines over the cited art for at least the reasons that the cited art fails to disclose the features emphasized above.

First, the selection of assessment item, the selection of data item for output, and the input items **received via a network** have been recited in the claims, and no corresponding teaching is disclosed in Aaron.

In addition, in the present application, in the individual reliability assessment, **a page of selections of assessment items is provided, and the client can select one of the assessment items for assessment via a network**. Each assessment item may have a plurality of data items, and **one of the data items can be selected for assessment output via the network**. **The related information (input items) of the remaining (unselected) data items of the assessment item without the selected data item** is received via the network. The reliability assessment for the selected assessment item is performed according to the **input items of the unselected data items, and the manufacturing process of the selected assessment item**. **The result of the reliability**

assessment comprises **at least one output item for the selected data item** of the selected assessment item.

It is clear that Aaron fails to disclose *related assessment selections and data are received via a network, a web-based interface providing selections for assisting identifying assessment items, the performance of reliability assessment based on input items of the unselected data items of the selected assessment item*, and generating a result of **output item for the unselected data item** of the selected assessment item.

For at least the foregoing reasons, independent claims 1, 16 and 31 patently define over the cited reference. Insofar as all remaining claims depend from either claim 1, claim 16, or claim 31, the rejections of the various dependent claims should be withdrawn for at least the same reasons. *In re Fine*, 837 F.2d 1071, 5 U.S.P.Q.2d 1596, 1600 (Fed. Cir. 1988).

CONCLUSION

In view of the foregoing, it is believed that all pending claims are in proper condition for allowance. If the Examiner believes that a telephone conference would expedite the examination of the above-identified patent application, the Examiner is invited to call the undersigned.

A credit card authorization is provided to cover the fee associated with the accompanying RCE application. No additional fee is believed to be due in connection with this submission. If, however, any additional fee is deemed to be payable, you are hereby authorized to charge any such fee to Deposit Account No. 20-0778.

Respectfully submitted,

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